

Search Notes

Application/Control No.

10/530,339

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

FURUKOSHI ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
363	16		
	20-21.18		
	49		
	97		
	131		
323	314		
	315		
	280	5/13/2006	/JH/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR